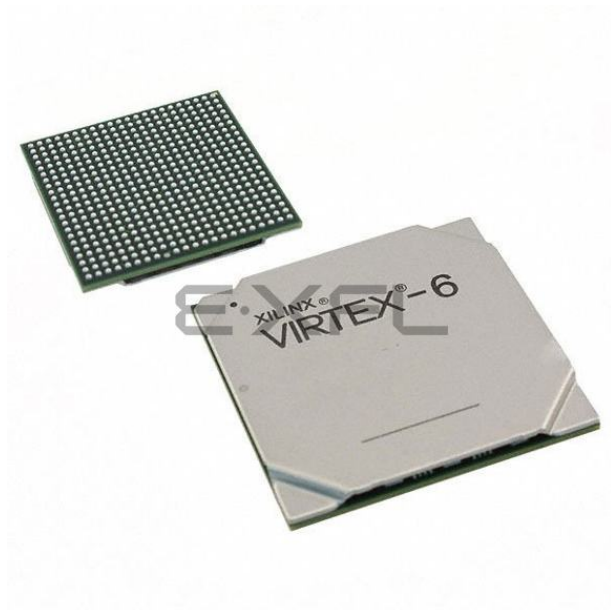




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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

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The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	18840
Number of Logic Elements/Cells	241152
Total RAM Bits	15335424
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx240t-1ff784i

Important Note

Typical values for quiescent supply current are specified at nominal voltage, 85°C junction temperatures (T_j). Xilinx recommends analyzing static power consumption at $T_j = 85^\circ\text{C}$ because the majority of designs operate near the high end of the commercial temperature range. Quiescent supply current is specified by speed grade for Virtex-6 devices. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified in Table 4.

Table 4: Typical Quiescent Supply Current

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC6VLX75T	927	927	927	N/A	656	741	mA
		XC6VLX130T	1563	1563	1563	N/A	1102	1245	mA
		XC6VLX195T	2059	2059	2059	N/A	1441	1628	mA
		XC6VLX240T	2478	2478	2478	N/A	1733	1957	mA
		XC6VLX365T	3001	3001	3001	N/A	2092	2363	mA
		XC6VLX550T ⁽³⁾	N/A	4515	4515	N/A	3147	3555	mA
		XC6VLX760 ⁽³⁾	N/A	5094	5094	N/A	3471	3921	mA
		XC6VSX315T	3476	3476	3476	N/A	2409	2721	mA
		XC6VSX475T ⁽³⁾	N/A	5227	5227	N/A	3622	4091	mA
		XC6VHX250T	2906	2906	2906	N/A	N/A	N/A	mA
		XC6VHX255T	2746	2746	2746	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	4160	4160	4160	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	5207	5207	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1563	N/A	1563	N/A	1245	mA
		XQ6VLX240T	N/A	2478	N/A	2478	N/A	1957	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	4515	N/A	3555	mA
		XQ6VSX315T	N/A	3476	N/A	3476	N/A	2721	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	5227	N/A	4091	mA

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I _{CCOQ}	Quiescent V _{CCO} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Table 16: GTX Transceiver Quiescent Supply Current (per Lane) ⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Typ ⁽⁴⁾	Max	Units
$I_{MGTAVTTQ}$	Quiescent MGTAVTT supply current for one GTX transceiver	0.9	Note 2	mA
$I_{MGTAVCCQ}$	Quiescent MGTAVCC supply current for one GTX transceiver	3.5		mA

Notes:

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.
3. GTX transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTX transceivers.
4. Typical values are specified at nominal voltage, 25°C.

GTX Transceiver DC Input and Output Levels

Table 17 summarizes the DC output specifications of the GTX transceivers in Virtex-6 FPGAs. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 17: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPIN}	Differential peak-to-peak input voltage	External AC coupled ≤ 4.25 Gb/s	125	–	2000	mV
		External AC coupled > 4.25 Gb/s	175	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled MGTAVTT = 1.2V	–400	–	MGTAVTT	mV
V_{CMIN}	Common mode input voltage	DC coupled MGTAVTT = 1.2V	–	2/3 MGTAVTT	–	mV
DV_{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage.	Equation based	$MGTAVTT - DV_{PPOUT}/4$			mV
R_{IN}	Differential input resistance		80	100	130	Ω
R_{OUT}	Differential output resistance		80	100	120	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	8	ps
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

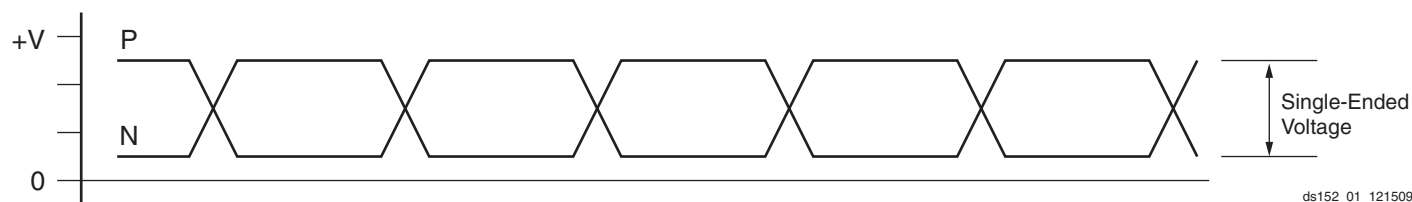


Figure 1: Single-Ended Peak-to-Peak Voltage

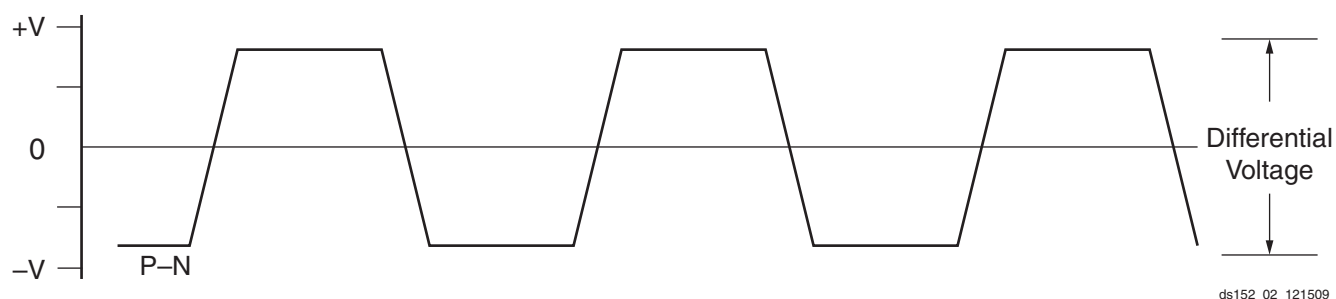


Figure 2: Differential Peak-to-Peak Voltage

Table 18 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 18: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	210	800	2000	mV
R_{IN}	Differential input resistance	90	100	130	Ω
C_{EXT}	Required external AC coupling capacitor	—	100	—	nF

GTX Transceiver Switching Characteristics

Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further information.

Table 19: GTX Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F_{GTXMAX}	Maximum GTX transceiver data rate	6.6	6.6	5.0	5.0	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	3.3 ⁽¹⁾	3.3 ⁽¹⁾	2.7	2.7	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	1.2	1.2	GHz

Notes:

- See Table 14 for MGTAVCC requirements when PLL frequency is greater than 2.7 GHz.

Table 20: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	150	150	125	100	MHz

Figure 4 shows the timing parameters in Table 27.

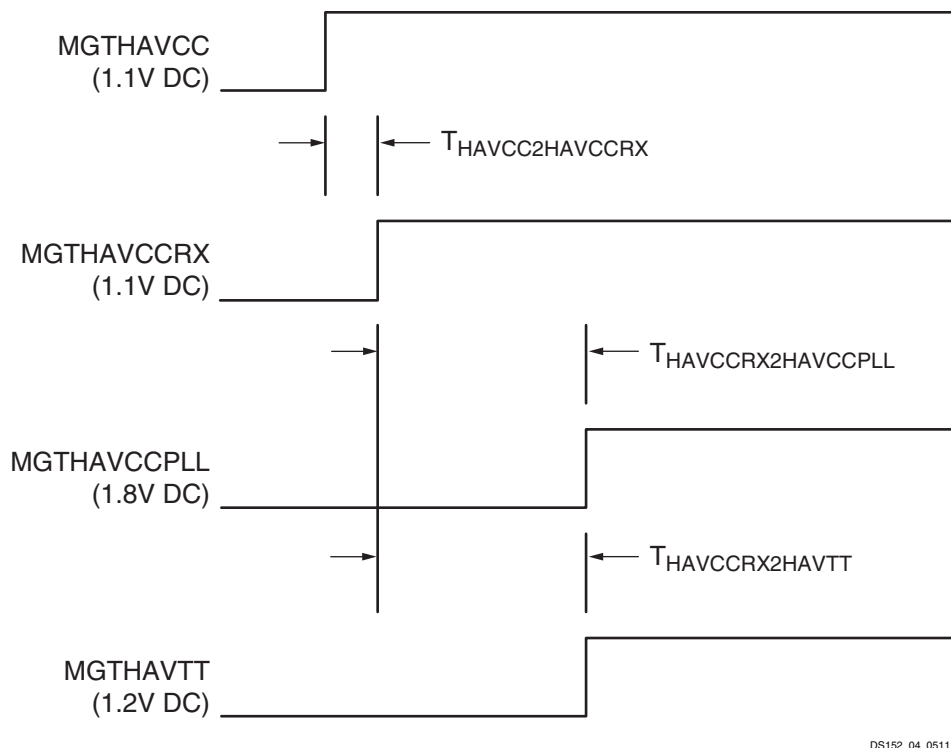


Figure 4: GTH Transceiver Power Supply Power-On Sequencing

Table 28: GTH Transceiver Supply Current

Symbol	Description	Typ ⁽¹⁾	Max	Units
$I_{MGTHAVCC}$	MGTHAVCC supply current for one GTH Quad (4 lanes)	571	Note 2	mA
$I_{MGTHAVCCR}$	MGTHAVCCR supply current for a GTH Quad (4 lanes)	254	Note 2	mA
$I_{MGTHAVTT}$	MGTHAVTT supply current for one GTH Quad (4 lanes)	93	Note 2	mA
$I_{MGTHAVCCPLL}$	MGTHAVCCPLL supply current for one GTH Quad (4 lanes)	219	Note 2	mA
$MGTR_{REF}$	Precision reference resistor for internal calibration termination	1000.0 ± 1% tolerance		Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C, with a 10.3125 Gb/s line rate.
2. Values for currents other than the values specified in this table can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 29: GTH Transceiver Quiescent Supply Current⁽¹⁾⁽²⁾

Symbol	Description	Typ ⁽³⁾	Max	Units
$I_{MGTHAVCCQ}$	Quiescent MGTHAVCC Supply Current for one GTH Quad (4 lanes)	65	Note 4	mA
$I_{MGTHAVCCRQ}$	Quiescent MGTHAVCCR Supply Current for one GTH Quad (4 lanes)	17	Note 4	mA
$I_{MGTHAVTTQ}$	Quiescent MGTHAVTT Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA
$I_{MGTHAVCCPLLQ}$	Quiescent MGTHAVCCPLL Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA

Notes:

1. Device powered and unconfigured.
2. GTH transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTH transceivers.
3. Typical values are specified at nominal voltage, 25°C.
4. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

1. Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	—	645	MHz
		-2 and -3 speed grades	150	—	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	—	—	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	—	—	20	μs

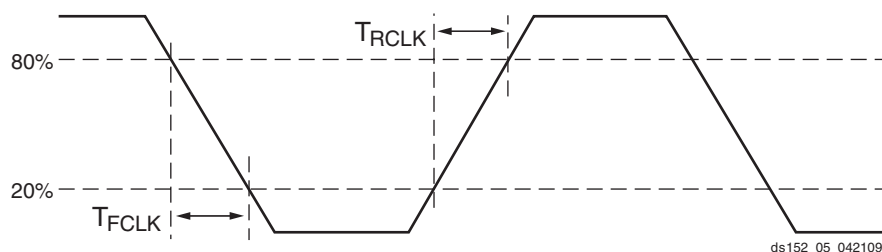


Figure 5: Reference Clock Timing Parameters

Table 35: GTH Transceiver User Clock Switching Characteristics ⁽¹⁾

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F _{TXOUT}	TXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz

Notes:

1. Clocking must be implemented as described in [UG371](#): Virtex-6 FPGA GTH Transceivers User Guide.

Table 36: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T _{RTX}	TX Rise time	20%–80%	–	50 ⁽³⁾	–	ps
T _{FTX}	TX Fall time	80%–20%	–	50 ⁽³⁾	–	ps
T _{LLSKEW}	TX lane-to-lane skew	within one GTH Quad	–	–	300	ps
Transmitter Output Jitter⁽¹⁾⁽²⁾						
TJ _{11.18}	Total Jitter	11.181 Gb/s	–	–	0.280	UI
DJ _{11.18}	Deterministic Jitter		–	–	0.170	UI
TJ _{10.3125}	Total Jitter	10.3125 Gb/s	–	–	0.280	UI
DJ _{10.3125}	Deterministic Jitter		–	–	0.170	UI
TJ _{9.953}	Total Jitter	9.953 Gb/s	–	–	0.280	UI
DJ _{9.953}	Deterministic Jitter		–	–	0.170	UI
TJ _{2.667}	Total Jitter	2.667 Gb/s	–	–	0.110	UI
DJ _{2.667}	Deterministic Jitter		–	–	0.060	UI
TJ _{2.488}	Total Jitter	2.488 Gb/s	–	–	0.110	UI
DJ _{2.488}	Deterministic Jitter		–	–	0.060	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit-error ratio of 1e⁻¹².
3. Rise and fall times are specified at the transmitter package balls.

Table 40: Analog-to-Digital Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
Analog Inputs ⁽³⁾						
Dedicated Analog Inputs Input Voltage Range V _P - V _N		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	20	–	MHz
Auxiliary Analog Inputs Input Voltage Range V _{AUXP[0]} / V _{AUXN[0]} to V _{AUXP[15]} / V _{AUXN[15]} T _j = –55°C to 125°C		Unipolar Operation	0	–	1	Volts
		Bipolar Operation	–0.5	–	+0.5	
		Unipolar Common Mode Range (FS input)	0	–	+0.5	
		Bipolar Common Mode Range (FS input)	+0.5	–	+0.6	
		Bandwidth	–	10	–	kHz
Input Leakage Current		A/D not converting, ADCCLK stopped	–	±1.0	–	µA
Input Capacitance			–	10	–	pF
On-chip Supply Monitor Error		V _{CCINT} and V _{CCAUX} with calibration enabled. External 1.25V reference T _j = –55°C to 125°C.	–	–	±1.0	% Reading
		V _{CCINT} and V _{CCAUX} with calibration enabled. Internal reference T _j = –40°C to 100°C. ⁽⁴⁾	–	±2	–	% Reading
On-chip Temperature Monitor Error		T _j = –55°C to +125°C with calibration enabled. External 1.25V reference.	–	–	±4	°C
		T _j = –40°C to +100°C with calibration enabled. Internal reference. ⁽⁴⁾	–	±5	–	°C
External Reference Inputs ⁽⁵⁾						
Positive Reference Input Voltage Range	V _{REFP}	Measured Relative to V _{REFN}	1.20	1.25	1.30	Volts
Negative Reference Input Voltage Range	V _{REFN}	Measured Relative to AGND	–50	0	100	mV
Input current	I _{REF}	ADCCLK = 5.2 MHz	–	–	100	µA
Power Requirements						
Analog Power Supply	AV _{DD}	Measured Relative to AV _{SS}	2.375	2.5	2.625	Volts
Analog Supply Current	AI _{DD}	ADCCLK = 5.2 MHz	–	–	12	mA

Notes:

- Offset errors are removed by enabling the System Monitor automatic gain calibration feature.
- See "System Monitor Timing" in [UG370: Virtex-6 FPGA System Monitor User Guide](#)
- See "Analog Inputs" in [UG370: Virtex-6 FPGA System Monitor User Guide](#) for a detailed description.
- These internal references are not specified over the junction temperature operating range for military (M) temperature devices.
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 26](#).

Table 41: Interface Performances

Description	Speed Grade			
	-3	-2	-1	-1L
Networking Applications				
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.4 Gb/s	1.3 Gb/s	1.25 Gb/s	1.1 Gb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1.4 Gb/s	1.3 Gb/s	1.1 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽²⁾⁽³⁾⁽⁴⁾				
DDR2	800 Mb/s	800 Mb/s	800 Mb/s	606 Mb/s
DDR3	1066 Mb/s	1066 Mb/s	800 Mb/s	800 Mb/s
QDR II + SRAM	400 MHz	350 MHz	300 MHz	—
RLDRAM II	500 MHz	400 MHz	350 MHz	—

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Verified on Xilinx memory characterization platforms designed according to the guidelines in UG: *Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult [DS186](#); *Virtex-6 FPGA Memory Interface Solutions Data Sheet* for performance and feature information on memory interface cores (controller plus PHY).
4. Memory Interface data rates have not been tested over the junction temperature operating range for military (M) temperature devices. Customers are responsible for specifying and testing their specific M temperature grade memory implementation.

IOB Pad Input/Output/3-State Switching Characteristics

Table 44 (for commercial (XC) Virtex-6 devices) and **Table 45** (for the Defense-grade (XQ) Virtex-6 devices) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.

T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.

T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer.

Table 46 summarizes the value of T_{IOTPHZ} . T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state).

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVDS_25	0.85	0.94	1.09	1.08	1.45	1.54	1.68	1.62	1.45	1.54	1.68	1.62	ns
LVDSEXT_25	0.85	0.94	1.09	1.08	1.53	1.65	1.84	1.73	1.53	1.65	1.84	1.73	ns
HT_25	0.85	0.94	1.09	1.08	1.51	1.62	1.78	1.69	1.51	1.62	1.78	1.69	ns
BLVDS_25	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.65	1.39	1.50	1.67	1.65	ns
RSDS_25 (point to point)	0.85	0.94	1.09	1.08	1.45	1.54	1.68	1.62	1.45	1.54	1.68	1.62	ns
HSTL_I	0.81	0.91	1.06	1.06	1.45	1.56	1.73	1.71	1.45	1.56	1.73	1.71	ns
HSTL_II	0.81	0.91	1.06	1.06	1.44	1.56	1.74	1.72	1.44	1.56	1.74	1.72	ns
HSTL_III	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
HSTL_I_18	0.81	0.91	1.06	1.06	1.47	1.58	1.75	1.72	1.47	1.58	1.75	1.72	ns
HSTL_II_18	0.81	0.91	1.06	1.06	1.50	1.62	1.81	1.78	1.50	1.62	1.81	1.78	ns
HSTL_III_18	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
SSTL2_I	0.81	0.91	1.06	1.06	1.49	1.60	1.77	1.74	1.49	1.60	1.77	1.74	ns
SSTL2_II	0.81	0.91	1.06	1.06	1.42	1.54	1.72	1.71	1.42	1.54	1.72	1.71	ns
SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
LVC MOS25, Slow, 2 mA	0.51	0.57	0.66	0.70	5.09	5.46	6.01	5.63	5.09	5.46	6.01	5.63	ns
LVC MOS25, Slow, 4 mA	0.51	0.57	0.66	0.70	3.30	3.49	3.79	3.65	3.30	3.49	3.79	3.65	ns
LVC MOS25, Slow, 6 mA	0.51	0.57	0.66	0.70	2.62	2.81	3.08	2.95	2.62	2.81	3.08	2.95	ns
LVC MOS25, Slow, 8 mA	0.51	0.57	0.66	0.70	2.21	2.41	2.72	2.59	2.21	2.41	2.72	2.59	ns
LVC MOS25, Slow, 12 mA	0.51	0.57	0.66	0.70	1.80	1.95	2.17	2.10	1.80	1.95	2.17	2.10	ns
LVC MOS25, Slow, 16 mA	0.51	0.57	0.66	0.70	1.89	2.05	2.29	2.21	1.89	2.05	2.29	2.21	ns
LVC MOS25, Slow, 24 mA	0.51	0.57	0.66	0.70	1.68	1.82	2.02	1.98	1.68	1.82	2.02	1.98	ns
LVC MOS25, Fast, 2 mA	0.51	0.57	0.66	0.70	5.12	5.49	6.04	5.62	5.12	5.49	6.04	5.62	ns
LVC MOS25, Fast, 4 mA	0.51	0.57	0.66	0.70	3.28	3.50	3.82	3.65	3.28	3.50	3.82	3.65	ns
LVC MOS25, Fast, 6 mA	0.51	0.57	0.66	0.70	2.56	2.73	2.99	2.88	2.56	2.73	2.99	2.88	ns
LVC MOS25, Fast, 8 mA	0.51	0.57	0.66	0.70	2.11	2.33	2.65	2.53	2.11	2.33	2.65	2.53	ns
LVC MOS25, Fast, 12 mA	0.51	0.57	0.66	0.70	1.74	1.88	2.08	2.03	1.74	1.88	2.08	2.03	ns
LVC MOS25, Fast, 16 mA	0.51	0.57	0.66	0.70	1.77	1.92	2.13	2.08	1.77	1.92	2.13	2.08	ns

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 6 and Figure 7.

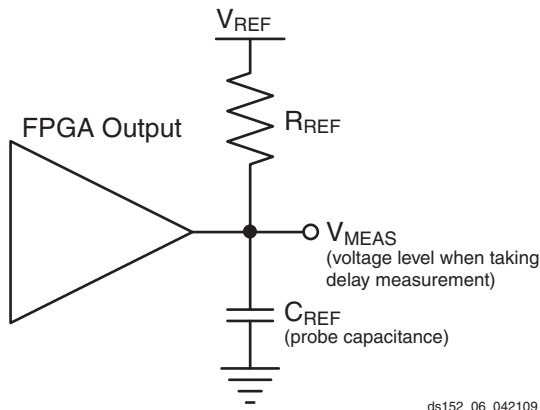
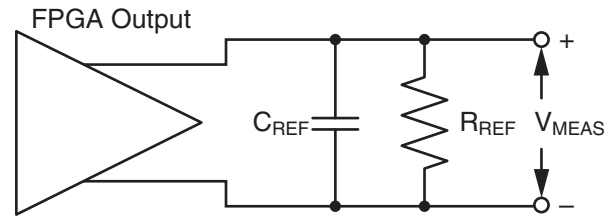


Figure 6: Single Ended Test Setup



ds152_07_042109

Figure 7: Differential Test Setup

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF} , R_{REF} , C_{REF} , and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 48.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 48: Output Delay Measurement Methodology

Description	I/O Standard Attribute	R_{REF} (Ω)	$C_{REF}^{(1)}$ (pF)	V_{MEAS} (V)	V_{REF} (V)
LVC MOS, 2.5V	LVC MOS25	1M	0	1.25	0
LVC MOS, 1.8V	LVC MOS18	1M	0	0.9	0
LVC MOS, 1.5V	LVC MOS15	1M	0	0.75	0
LVC MOS, 1.2V	LVC MOS12	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
LVDS EXT (LVDS Extended Mode), 2.5V	LVDS_25	100	0	0 ⁽²⁾	1.2
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 ⁽²⁾	0

Output Serializer/Deserializer Switching Characteristics

Table 52: OSERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold							
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.23/ −0.10	0.28/ −0.10	0.31/ −0.10	0.35/ −0.10	0.36/ −0.15	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.44/ −0.10	0.51/ −0.09	0.56/ −0.08	0.60/ −0.08	0.68/ −0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.25/ −0.10	0.27/ −0.09	0.31/ −0.08	0.31/ −0.08	0.47/ −0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.17/ −0.03	0.20/ −0.03	0.22/ −0.03	0.27/ −0.03	0.27/ −0.04	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.07	0.07	0.07	0.07	0.08	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.15/ −0.04	0.19/ −0.04	0.21/ −0.04	0.27/ −0.04	0.29/ −0.05	ns
Sequential Delays							
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.63	0.71	0.82	0.82	0.93	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.63	0.71	0.82	0.82	0.93	ns
Combinatorial							
T _{OSDO_TTQ}	T input to TQ Out	0.76	0.84	0.97	0.97	1.11	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Input/Output Delay Switching Characteristics

Table 53: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.00	3.00	3.00	3.25	μs
F _{IDELAYCTRL_REF}	REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	200	MHz
	REFCLK frequency = 300.0 ⁽¹⁾	300	300	–	–	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	50.00	50.00	50.00	52.50	ns
IODELAY						
T _{IDELAYRESOLUTION}	IODELAY Chain Delay Resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23). ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IODELAY_CLK_MAX}	Maximum frequency of CLK input to IODELAY	500.00	420.00	300.00	300.00	MHz
T _{IODCCK_CE} / T _{IODCKC_CE}	CE pin Setup/Hold with respect to CK	0.45/ –0.09	0.53/ –0.09	0.65/ –0.09	0.84/ –0.14	ns
T _{IODCK_INC} / T _{IODCKC_INC}	INC pin Setup/Hold with respect to CK	0.23/ –0.02	0.27/ –0.01	0.31/ 0.00	0.27/ –0.04	ns
T _{IODCCK_RST} / T _{IODCKC_RST}	RST pin Setup/Hold with respect to CK	0.57/ –0.08	0.62/ –0.08	0.69/ –0.08	0.74/ –0.13	ns
T _{IODDO_T}	TSCONTROL delay to MUXE/MUXF switching and through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_IDATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{IODDO_ODATAIN}	Propagation delay through IODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY tap setting. See TRACE report for actual values.

CLB Switching Characteristics

Table 54: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Combinatorial Delays						
T _{ILO}	An – Dn LUT address to A	0.06	0.07	0.07	0.09	ns, Max
	An – Dn LUT address to AMUX/CMUX	0.18	0.20	0.22	0.25	ns, Max
	An – Dn LUT address to BMUX_A	0.28	0.31	0.36	0.40	ns, Max

Table 54: CLB Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{ITO}	An – Dn inputs to A – D Q outputs	0.59	0.67	0.79	0.85	ns, Max
T _{AXA}	AX inputs to AMUX output	0.31	0.35	0.42	0.44	ns, Max
T _{AXB}	AX inputs to BMUX output	0.35	0.39	0.47	0.50	ns, Max
T _{AXC}	AX inputs to CMUX output	0.39	0.44	0.52	0.56	ns, Max
T _{AXD}	AX inputs to DMUX output	0.42	0.47	0.55	0.60	ns, Max
T _{BXB}	BX inputs to BMUX output	0.30	0.34	0.39	0.44	ns, Max
T _{BXD}	BX inputs to DMUX output	0.38	0.43	0.50	0.55	ns, Max
T _{CXC}	CX inputs to CMUX output	0.26	0.29	0.34	0.37	ns, Max
T _{CXD}	CX inputs to DMUX output	0.30	0.34	0.40	0.44	ns, Max
T _{DXD}	DX inputs to DMUX output	0.30	0.33	0.38	0.43	ns, Max
T _{OPCYA}	An input to COUT output	0.32	0.36	0.41	0.47	ns, Max
T _{OPCYB}	Bn input to COUT output	0.32	0.36	0.41	0.47	ns, Max
T _{OPCYC}	Cn input to COUT output	0.27	0.30	0.34	0.40	ns, Max
T _{OPCYD}	Dn input to COUT output	0.25	0.28	0.32	0.37	ns, Max
T _{AXCY}	AX input to COUT output	0.25	0.28	0.33	0.36	ns, Max
T _{BXCY}	BX input to COUT output	0.22	0.24	0.28	0.31	ns, Max
T _{CXCY}	CX input to COUT output	0.15	0.17	0.20	0.22	ns, Max
T _{DXCY}	DX input to COUT output	0.14	0.16	0.19	0.21	ns, Max
T _{BYP}	CIN input to COUT output	0.06	0.07	0.08	0.09	ns, Max
T _{CINA}	CIN input to AMUX output	0.21	0.24	0.28	0.30	ns, Max
T _{CINB}	CIN input to BMUX output	0.23	0.25	0.29	0.31	ns, Max
T _{CINC}	CIN input to CMUX output	0.23	0.26	0.30	0.33	ns, Max
T _{CIND}	CIN input to DMUX output	0.25	0.29	0.33	0.36	ns, Max
Sequential Delays						
T _{CKO}	Clock to AQ – DQ outputs	0.29	0.33	0.39	0.44	ns, Max
T _{SHCKO}	Clock to AMUX – DMUX outputs	0.36	0.40	0.47	0.53	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T _{DICK} /T _{CKDI}	A – D input to CLK on A – D Flip Flops	0.30/0.17	0.36/0.18	0.43/0.20	0.44/0.25	ns, Min
T _{CECK_CLB} / T _{CKCE_CLB}	CE input to CLK on A – D Flip Flops	0.20/0.00	0.25/0.00	0.32/0.00	0.32/0.01	ns, Min
T _{SRCK} /T _{CKSR}	SR input to CLK on A – D Flip Flops	0.39/–0.07	0.44/–0.07	0.52/–0.07	0.58/–0.08	ns, Min
T _{CINCK} /T _{CKCIN}	CIN input to CLK on A – D Flip Flops	0.16/0.12	0.19/0.14	0.24/0.16	0.23/0.22	ns, Min
Set/Reset						
T _{SRMIN}	SR input minimum pulse width	0.90	0.90	0.97	0.80	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.52	0.58	0.68	0.77	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.41	0.48	0.59	0.61	ns, Max
F _{TOG}	Toggle frequency (for export control)	1412.00	1286.40	1098.00	1098.00	MHz

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. These items are of interest for Carry Chain applications.

Block RAM and FIFO Switching Characteristics

Table 57: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.60	1.79	2.08	2.36	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.60	0.66	0.75	0.83	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.62	2.89	3.30	3.73	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.71	0.77	0.86	0.94	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.49	2.77	3.18	3.61	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.29	1.41	1.58	1.79	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.74	0.81	0.91	0.98	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.90	0.98	1.09	1.21	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.62	0.68	0.76	0.82	ns, Max
	Clock CLK to BITERR (without output register)	2.21	2.46	2.84	3.23	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.86	0.94	1.06	1.18	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.73	0.79	0.90	1.00	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.76	0.82	0.92	1.02	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.47/ 0.27	0.53/ 0.29	0.62/ 0.32	0.66/ 0.34	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	0.84/ 0.30	0.95/ 0.32	1.11/ 0.34	1.26/ 0.36	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.47/ 0.30	0.52/ 0.32	0.59/ 0.34	0.68/ 0.36	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.68/ 0.30	0.75/ 0.32	0.85/ 0.34	0.97/ 0.36	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.77/ 0.30	0.87/ 0.32	1.02/ 0.34	1.16/ 0.36	ns, Min
T _{RCKC_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	0.90/ 0.27	1.02/ 0.28	1.20/ 0.29	1.56/ 0.29	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.31/ 0.26	0.35/ 0.27	0.41/ 0.30	0.44/ 0.31	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.18/ 0.25	0.19/ 0.27	0.22/ 0.31	0.24/ 0.33	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/ 0.23	0.36/ 0.24	0.41/ 0.27	0.46/ 0.29	ns, Min

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{DSPDO_PCIN, CARRYCASCIN, MULTSIGNIN_PCOUT, CARRYCASCO, MULTSIGNOUT}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCO, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
Clock to Outs from Output Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_PREG}$	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_PREG}$	CLK (PREG) to {CARRYCASCO, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
Clock to Outs from Pipeline Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_MREG}$	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_MREG}$	CLK (MREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
$T_{DSPCKO_P, CARRYOUT_ADREG_MULT}$	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_ADREG_MULT}$	CLK (ADREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
Clock to Outs from Input Register Clock to Output Pins							
$T_{DSPCKO_P, CARRYOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
$T_{DSPCKO_P, CARRYOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
$T_{DSPCKO_P, CARRYOUT_CREG}$	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
$T_{DSPCKO_P, CARRYOUT_DREG_MULT}$	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
Clock to Outs from Input Register Clock to Cascading Output Pins							
$T_{DSPCKO_ACOUT, BCOUT_AREG, BREG}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_AREG, BREG_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_AREG, BREG}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_DREG_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
$T_{DSPCKO_PCOUT, CARRYCASCO, MULTSIGNOUT_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCO, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F _{MAX}	With all registers used	600	540	450	450	410	MHz
F _{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	356	311	262	262	224	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	398	347	292	292	254	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	398	347	292	292	254	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program Latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T _{ICCK}	CCLK (output) delay	400	400	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T _{DCCK} /T _{CCKD}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T _{DSCCK} /T _{SCCKD}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T _{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F _{MSCCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T _{SMDCK} /T _{SMCKD}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCSCCK} /T _{SMCKCS}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCCKW} /T _{SMWCK}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T _{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 67: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Clock-capable Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
T _{ICKOFMMCMCC}	Clock-capable Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.22	2.38	2.63	2.72	ns
		XC6VLX130T	2.24	2.39	2.65	2.74	ns
		XC6VLX195T	2.24	2.40	2.65	2.75	ns
		XC6VLX240T	2.24	2.40	2.65	2.75	ns
		XC6VLX365T	2.25	2.42	2.65	2.76	ns
		XC6VLX550T	N/A	2.43	2.68	2.80	ns
		XC6VLX760	N/A	2.42	2.69	2.79	ns
		XC6VSX315T	2.23	2.38	2.65	2.73	ns
		XC6VSX475T	N/A	2.30	2.57	2.66	ns
		XC6VHX250T	2.25	2.41	2.67	N/A	ns
		XC6VHX255T	2.35	2.51	2.78	N/A	ns
		XC6VHX380T	2.27	2.43	2.69	N/A	ns
		XC6VHX565T	N/A	2.41	2.68	N/A	ns
		XQ6VLX130T	N/A	2.39	2.65	2.74	ns
		XQ6VLX240T	N/A	2.40	2.65	2.75	ns
		XQ6VLX550T	N/A	N/A	2.68	2.80	ns
		XQ6VSX315T	N/A	2.38	2.65	2.73	ns
		XQ6VSX475T	N/A	N/A	2.57	2.66	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T_{BUFIO_SKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T_{BUFIO_SKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

1. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
2. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock	−0.28/1.09	−0.28/1.16	−0.28/1.33	−0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFIO						
T _{ICKOFCs}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V_{CCAUX} and V_{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T_{DLYCCO_RDY} , $T_{IDELAYCTRL_RPW}$, and $T_{IDELAYPAT_JIT}$ in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T_{TAPTCK}/T_{TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V_{FS} and notes to Table 1 and Table 2 . Removed DV_{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F_{MAX} section in Table 57, page 44 including removing Note 12. Changed F_{PFDMAX} values and corrected units for $T_{STATPHAOFFSET}$ and $T_{OUTDUTY}$ in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV_{PPOUT} and revised description of T_{OSKEW} in Table 17 . Removed V_{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T_{IOTPHZ} in Table 46 . Removed $T_{BUFHSKEW}$ from Table 71, page 60 and added values for $T_{BUFIOSKEW}$. Added values in Table 74 .